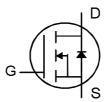


## N-CHANNEL ENHANCEMENT-MODE POWER MOSFET

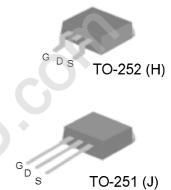
Low gate-charge Simple drive requirement Fast switching



BV<sub>DSS</sub> 30V  $12m\Omega$ R<sub>DS(ON)</sub> 45A  $I_D$ 

# **Description**

The SSM60T03H is in a TO-252 package, which is widely used for commercial and industrial surface mount applications, and is well suited for low voltage applications such as DC/DC converters. The through-hole version, the SSM60T03J in TO-251, is available for low-footprint vertical mounting. These devices are manufactured with an advanced process, providing improved on-resistance and switching performance. The devices have a maximum junction temperature rating of 175°C for improved thermal margin and reliability.



**Absolute Maximum Ratings** 

Symbol	Parameter	Rating	Units
$V_{ m DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	±20	V
I <sub>D</sub> @ T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	45	Α
I <sub>D</sub> @ T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	32	Α
I <sub>DM</sub>	Pulsed Drain Current <sup>1</sup>	120	Α
P <sub>D</sub> @ T <sub>C</sub> =25°C	Total Power Dissipation	44	W
	Linear Derating Factor	0.352	W/°C
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>3</sup>	29	mJ
$T_{STG}$	Storage Temperature Range	-55 to 175	°C
TJ	Operating Junction Temperature Range	-55 to 175	°C

### **Thermal Data**

Symbol	Parameter	Max.	Units	
Rthj-c	Thermal Resistance Junction-case	3.4	°C/W	] .
Rthj-a	Thermal Resistance Junction-ambient	110	°C/W	]_0
			-0	
04 Rev.2.1	www SiliconStandard com	C	heeth	1 of
004 Rev.2.1	www.SiliconStandard.com	MMN Daja	heer	1 (



# Electrical Characteristics @ T<sub>j</sub>=25°C (unless otherwise specified)

	<u> </u>					
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ =0V, $I_D$ =250uA	30	-	-	V
$\Delta$ BV $_{ m DSS}/\Delta\!\!$ T j	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I□=1mA	-	0.026	-	V/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}$ =10V, $I_D$ =20A	-	-	12	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =15A	-	-	25	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=250$ uA	1	-	3	V
$g_{fs}$	Forward Transconductance <sup>2</sup>	$V_{DS}$ =10V, $I_D$ =10A	-	25	-	S
I <sub>DSS</sub>	Drain-Source Leakage Current (T <sub>i</sub> =25°C)	$V_{\rm DS}$ =30V, $V_{\rm GS}$ =0V	-	-	1	uA
	Drain-Source Leakage Current (T <sub>j</sub> =175 <sup>o</sup> C)	$V_{DS}$ =24V , $V_{GS}$ =0V	-	-	250	uA
$I_{GSS}$	Gate-Source Leakage	$V_{GS}$ = ± 20 $V$	-	-	±100	nA
$Q_g$	Total Gate Charge <sup>2</sup>	I <sub>D</sub> =20A	-	11.6	-	nC
$Q_{gs}$	Gate-Source Charge	V <sub>DS</sub> =24V	-	3.9	-	nC
$Q_{gd}$	Gate-Drain ("Miller") Charge	V <sub>GS</sub> =4.5V	-	7	-	nC
$t_{d(on)}$	Turn-on Delay Time <sup>2</sup>	V <sub>DS</sub> =15V	-	8.8	-	ns
t <sub>r</sub>	Rise Time	I <sub>D</sub> =20A	-	57.5	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_G$ =3.3 $\Omega$ , $V_{GS}$ =10 $V$	-	18.5	-	ns
t <sub>f</sub>	Fall Time	$R_D$ =0.75 $\Omega$	-	6.4	-	ns
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V	-	1135	-	рF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =25V	-	200	-	рF
C <sub>rss</sub>	Reverse Transfer Capacitance	f=1.0MHz	-	135	-	рF

## **Source-Drain Diode**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
$V_{ ext{SD}}$	Forward On Voltage <sup>2</sup>	$I_S$ =45A, $V_{GS}$ =0V	-	ı	1.3	٧
trr	Reverse Recovery Time	I <sub>S</sub> =20A, V <sub>GS</sub> =0V,	-	23.3	-	ns
Qrr	Reverse Recovery Charge	dl/dt=100A/µs	-	16	-	nC

### Notes:

- 1. Pulse width limited by safe operating area.
- 2.Pulse width ≤300us , duty cycle ≤2%.
- $3.V_{DD}\text{=}25V$  , L=100uH ,  $R_{G}\text{=}25\Omega$  ,  $I_{AS}\text{=}24A.$



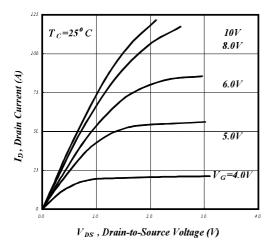


Fig 1. Typical Output Characteristics

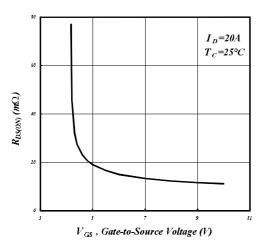


Fig 3. On-Resistance vs. Gate Voltage

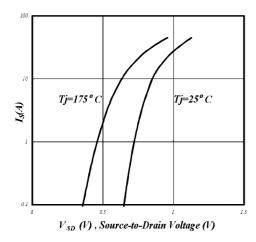


Fig 5. Forward Characteristic of Reverse Diode

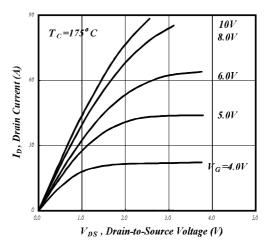


Fig 2. Typical Output Characteristics

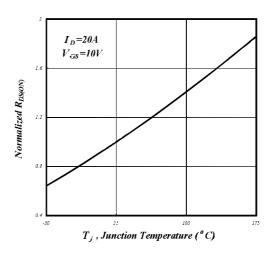


Fig 4. Normalized On-Resistance vs. Junction Temperature

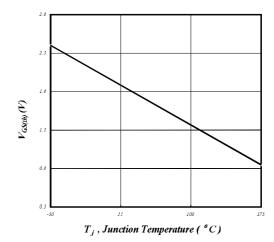


Fig 6. Gate Threshold Voltage vs. Junction Temperature



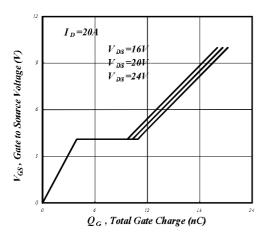


Fig 7. Gate Charge Characteristics

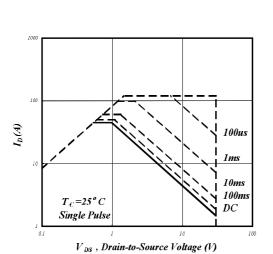


Fig 9. Maximum Safe Operating Area

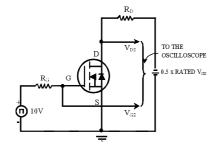


Fig 11. Switching Time Circuit

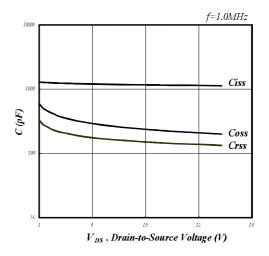


Fig 8. Typical Capacitance Characteristics

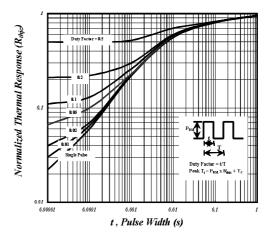


Fig 10. Effective Transient Thermal Impedance

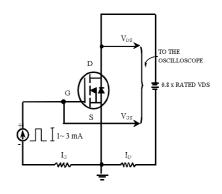


Fig 12. Gate Charge Circuit





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